

LME49860 44V Dual High Performance, High Fidelity Audio Operational Amplifier

General Description

The LME49860 is part of the ultra-low distortion, low noise, high slew rate operational amplifier series optimized and fully specified for high performance, high fidelity applications. Combining advanced leading-edge process technology with state-of-the-art circuit design, the LME49860 audio operational amplifiers deliver superior audio signal amplification for outstanding audio performance. The LME49860 combines extremely low voltage noise density ($2.7nV/\sqrt{Hz}$) with vanishingly low THD+N (0.00003%) to easily satisfy the most demanding audio applications. To ensure that the most challenging loads are driven without compromise, the LME49860 has a high slew rate of $\pm 20V/\mu$ s and an output current capability of ± 26 mA. Further, dynamic range is maximized by an output stage that drives $2k\Omega$ loads to within 1V of either power supply voltage and to within 1.4V when driving 600 Ω loads.

The LME49860's outstanding CMRR (120dB), PSRR (120dB), and V_{OS} (0.1mV) give the amplifier excellent operational amplifier DC performance.

The LME49860 has a wide supply range of $\pm 2.5V$ to $\pm 22V$. Over this supply range the LME49860 maintains excellent common-mode rejection, power supply rejection, and low input bias current. The LME49860 is unity gain stable. This Audio Operational Amplifier achieves outstanding AC performance while driving complex loads with values as high as 100pF.

The LME49860 is available in 8–lead narrow body SOIC and 8–lead Plastic DIP packages. Demonstration boards are available for each package.

Key Specifications

Power Supply Voltage Range

Typical Application

- THD+N
 - $(A_V = 1, V_{OUT} = 3V_{RMS}, f_{IN} = 1kHz)$

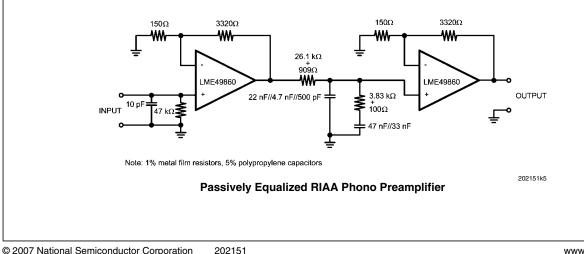
$R_L = 2k\Omega$	0.00003% (typ)		
R _L = 600Ω	0.00003% (typ)		
Input Noise Density	2.7nV/ $√$ Hz (typ)		
Slew Rate	±20V/μs (typ)		
Gain Bandwidth Product	55MHz (typ)		
■ Open Loop Gain (R _L = 600Ω)	140dB (typ)		
Input Bias Current	10nA (typ)		
Input Offset Voltage	0.1mV (typ)		
DC Gain Linearity Error	0.000009%		

Features

- Easily drives 600Ω loads
- Optimized for superior audio signal fidelity
- Output short circuit protection
- PSRR and CMRR exceed 120dB (typ)
- SOIC, DIP packages

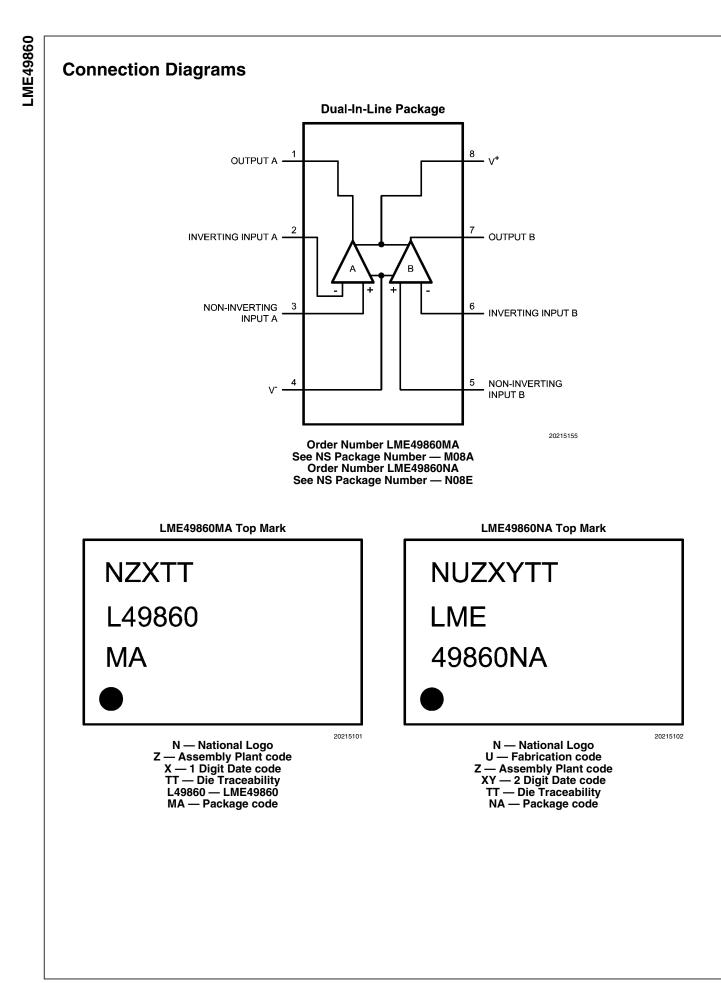
Applications

- Ultra high quality audio amplification
- High fidelity preamplifiers
- High fidelity multimedia
- State of the art phono pre amps
- High performance professional audio
- High fidelity equalization and crossover networks
- High performance line drivers
- High performance line receivers
- High fidelity active filters



±2.5V to ±22V

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Absolute Maximum Ratings (Notes 1, 2)

If Military/Aerospace specified devices are required, please contact the National Semiconductor Sales Office/ Distributors for availability and specifications.

Power Supply Voltage	
$(V_{S} = V^{+} - V^{-})$	46V
Storage Temperature	–65°C to 150°C
Input Voltage	(V-) - 0.7V to (V+) + 0.7V
Output Short Circuit (Note 3)	Continuous
ESD Susceptibility (Note 4)	2000V
ESD Susceptibility (Note 5)	
Pins 1, 4, 7 and 8	200V

Pins 2, 3, 5 and 6	100V	
Junction Temperature 150		
Thermal Resistance		
θ _{JA} (SO)	145°C/W	
θ _{JA} (NA)	102°C/W	

Operating Ratings

Temperature Range

$T_{MIN} \leq T_{A} \leq T_{MAX}$	$-40^{\circ}C \le T_A \le 85^{\circ}C$
Supply Voltage Range	$\pm 2.5 V \le V_S \le \pm 22 V$

Electrical Characteristics for the LME49860 (Note 1) The following specifications apply for $V_s = \pm 18V$ and $\pm 22V$, $R_L = 2k\Omega$, $R_{SOURCE} = 10\Omega$, $f_{IN} = 1$ kHz, $T_A = 25^{\circ}$ C, unless otherwise specified.

			LME49860		
Symbol	Parameter	Conditions	Typical Limit		Units
-			(Note 6)	(Note 7)	(Limits)
		$A_V = 1, V_{OUT} = 3V_{rms}$			
THD+N	Total Harmonic Distortion + Noise	$R_{I} = 2k\Omega$	0.00003		% (max)
		$R_{L} = 600\Omega$	0.00003	0.00009	
IMD	Intermodulation Distortion	A _V = 1, V _{OUT} = 3V _{RMS} Two-tone, 60Hz & 7kHz 4:1	0.00005		%
GBWP	Gain Bandwidth Product		55	45	MHz (min)
SR	Slew Rate		±20	±15	V/µs (min)
FPBW	Full Power Bandwidth	$V_{OUT} = 1V_{P-P}, -3dB$ referenced to output magnitude at f = 1kHz	10		MHz
t _s	Settling time	A _V = −1, 10V step, C _L = 100pF 0.1% error range	1.2		μs
	Equivalent Input Noise Voltage	f _{BW} = 20Hz to 20kHz	0.34	0.65	μV _{RMS} (max)
e _n	Equivalent Input Noise Density	f = 1kHz f = 10Hz	2.7 6.4	4.7	nV/√Hz (max)
i _n	Current Noise Density	f = 1kHz f = 10Hz	1.6 3.1		pA/√Hz
	6 //	$V_{\rm S} = \pm 18 V$	±0.12	±0.7	mV (max)
V _{OS}	Offset Voltage	$V_{\rm S} = \pm 22 V$	±0.14	±0.7	mV (max)
ΔV _{OS} /ΔTemp	Average Input Offset Voltage Drift vs Temperature	$-40^{\circ}\text{C} \le \text{T}_{\text{A}} \le 85^{\circ}\text{C}$	0.2		μV/°C
PSRR	Average Input Offset Voltage Shift vs Power Supply Voltage	(Note 8) $V_S = \pm 18V, \Delta V_S = 24V$ $V_S = \pm 22V, \Delta V_S = 30V$	120 120	110	dB dB (min)
ISO _{CH-CH}	Channel-to-Channel Isolation	f _{IN} = 1kHz f _{IN} = 20kHz	118 112		dB
IB	Input Bias Current	V _{CM} = 0V	10	72	nA (max)
ΔI _{OS} /ΔTemp	Input Bias Current Drift vs Temperature	$-40^{\circ}\text{C} \le \text{T}_{\text{A}} \le 85^{\circ}\text{C}$	0.1		nA/°C
I _{os}	Input Offset Current	V _{CM} = 0V	11	65	nA (max)
	Common-Mode Input Voltage Range	$V_{\rm S} = \pm 18V$	+17.1 -16.9	(V+) - 2.0 (V-) + 2.0	V (min) V (min)
V _{IN-CM}		$V_{\rm S} = \pm 22V$	+21.0 -20.8	(V+) - 2.0 (V-) + 2.0	V (min) V (min)

LME49860

			LME	LME49860	
Symbol	Parameter	Conditions	Typical		
•			(Note 6)	(Note 7)	(Limits)
		V _S = ±18V	100		
		$-12V \le V_{CM} \le 12V$	120		dB
CMRR	Common-Mode Rejection	$V_{\rm S} = \pm 22 V$			
		-15V ≤ V _{CM} ≤ 15V	120	110	dB (min
_	Differential Input Impedance		30		kΩ
Z _{IN}	Common Mode Input Impedance	-10V <vcm<10v< td=""><td>1000</td><td></td><td>MΩ</td></vcm<10v<>	1000		MΩ
	· ·	$V_{S} = \pm 18V$			
		–12V≤Vout≤12V			
		$R_1 = 600\Omega$	140		dB
		$R_{L} = 2k\Omega$	140		dB
	Open Loop Voltage Gain	$R_{L} = 10k\Omega$	140		dB
A _{VOL}		$V_{S} = \pm 22V$			
		_15V≤Vout≤15V			
		$R_1 = 600\Omega$	140	125	dB (min
		$R_1 = 2k\Omega$	140		dB (min
		$R_{L} = 10k\Omega$	140		dB
		R ₁ = 600Ω			
		$V_{\rm S} = \pm 18V$	±16.7		v
		$V_{\rm S} = \pm 22 V$	±20.4	±19.0	V (min)
		$R_1 = 2k\Omega$			
V _{OUTMAX}	Maximum Output Voltage Swing	$V_{S} = \pm 18V$	±17.0		v
		$V_{\rm S} = \pm 22 V$	±21.0		V
		$R_{I} = 10k\Omega$			
		$V_{\rm S} = \pm 18 V$	±17.1		v
		$V_{S} = \pm 22V$	±21.2		V
		R _L = 600Ω			
I _{OUT}	Output Current	$V_{S} = \pm 20V$	±31		mA
		$V_{\rm S} = \pm 22 V$	±37	±30	mA (min
	Instantaneous Short Circuit Current		+53		mA
I _{OUT-CC}			-42		
D		f _{IN} = 10kHz			
R _{OUT}	Output Impedance	Closed-Loop	0.01		Ω
<u> </u>	Capacitive Load Drive Overshoot	Open-Loop 100pF	13		0/
C _{LOAD}			16		%
	Total Quiescent Current	$I_{OUT} = 0mA$			
I _S	Total Quiescent Current	$V_{\rm S} = \pm 18V$ $V_{\rm S} = \pm 22V$	10.2	10	mA
		$V_{S} = \pm 22V$	10.5	13	mA (max

Note 1: Absolute Maximum Ratings indicate limits beyond which damage to the device may occur.

Note 2: Operating Ratings indicate conditions for which the device is functional, but do not guarantee specific performance limits. For guaranteed specifications and test conditions, see the Electrical Characteristics. The guaranteed specifications apply only for the test conditions listed. Some performance characteristics may degrade when the device is not operated under the listed test conditions.

Note 3: Amplifier output connected to GND, any number of amplifiers within a package.

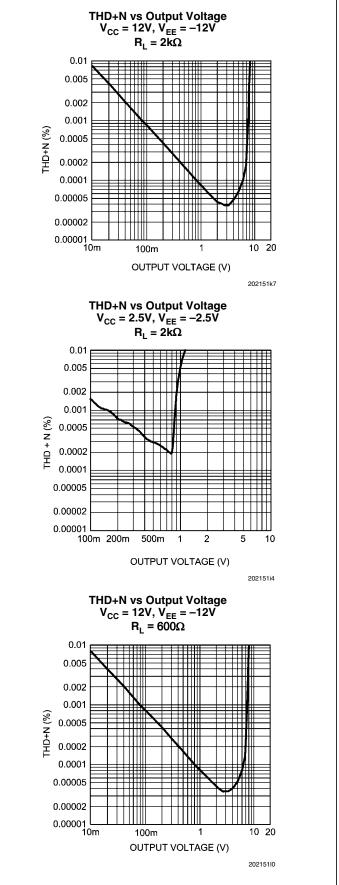
Note 4: Human body model, 100pF discharged through a 1.5k $\!\Omega$ resistor.

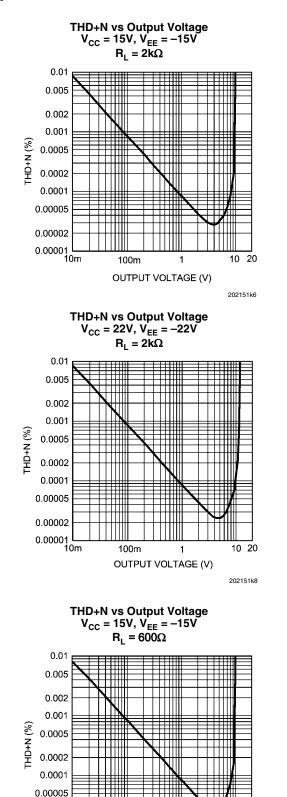
Note 5: Machine Model ESD test is covered by specification EIAJ IC-121-1981. A 200pF cap is charged to the specified voltage and then discharged directly into the IC with no external series resistor (resistance of discharge path must be under 50Ω).

Note 6: Typical specifications are specified at +25 $^{\circ}$ C and represent the most likely parametric norm.

Note 7: Tested limits are guaranteed to National's AOQL (Average Outgoing Quality Level).

Note 8: PSRR is measured as follows: For V_S = ±22V, V_{OS} is measured at two supply voltages, ±7V and ±22V. PSRR = | $20log(\Delta V_{OS}/\Delta V_{S})$ |.





Typical Performance Characteristics

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10 20

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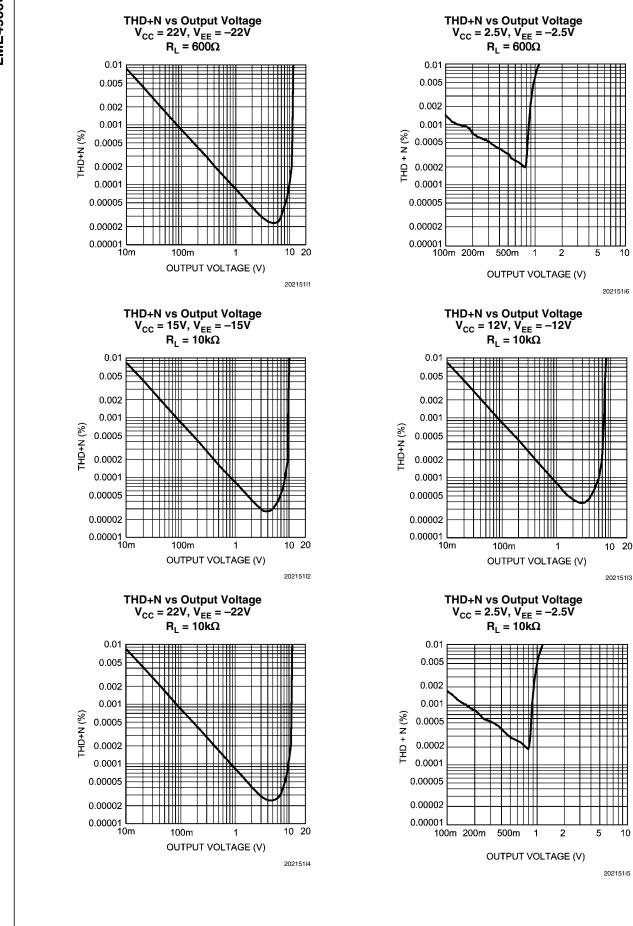
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0.00001 L 10m

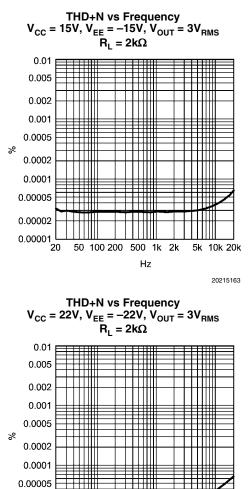
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OUTPUT VOLTAGE (V)



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50 100 200 500 1k 2k

THD+N vs Frequency

 $\bar{R}_L = 600\Omega$

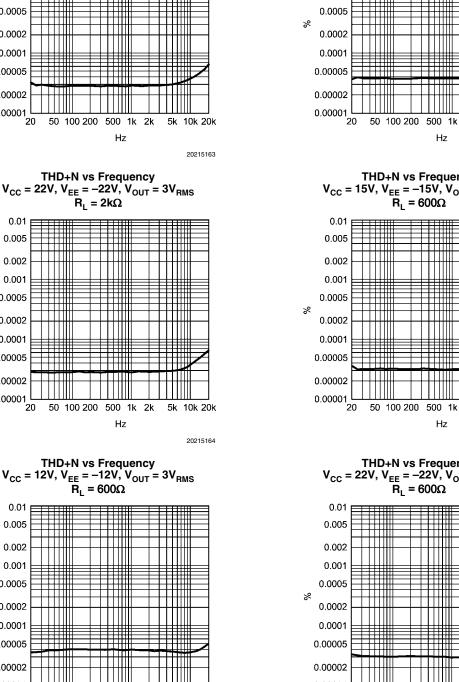
50 100 200 500 1k 2k

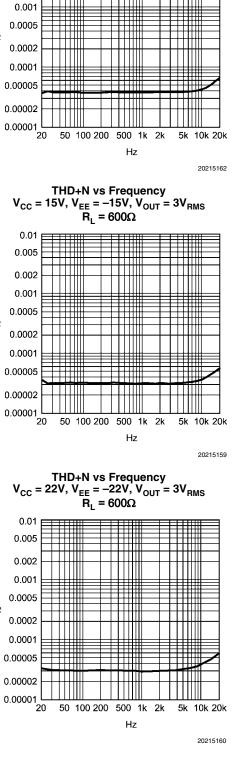
Hz

5k 10k 20k

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Hz





THD+N vs Frequency $V_{CC} = 12V, V_{EE} = -12V, V_{OUT} = 3V_{RMS}$

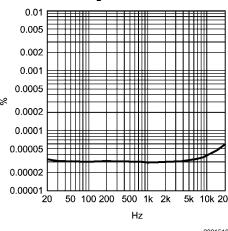
 $R_L = 2k\Omega$

Ш

0.01

0.005

0.002



0.00002

0.00001

0.01

0.005

0.002

0.001

0.0005

0.0002

0.0001

0.00005

0.00002

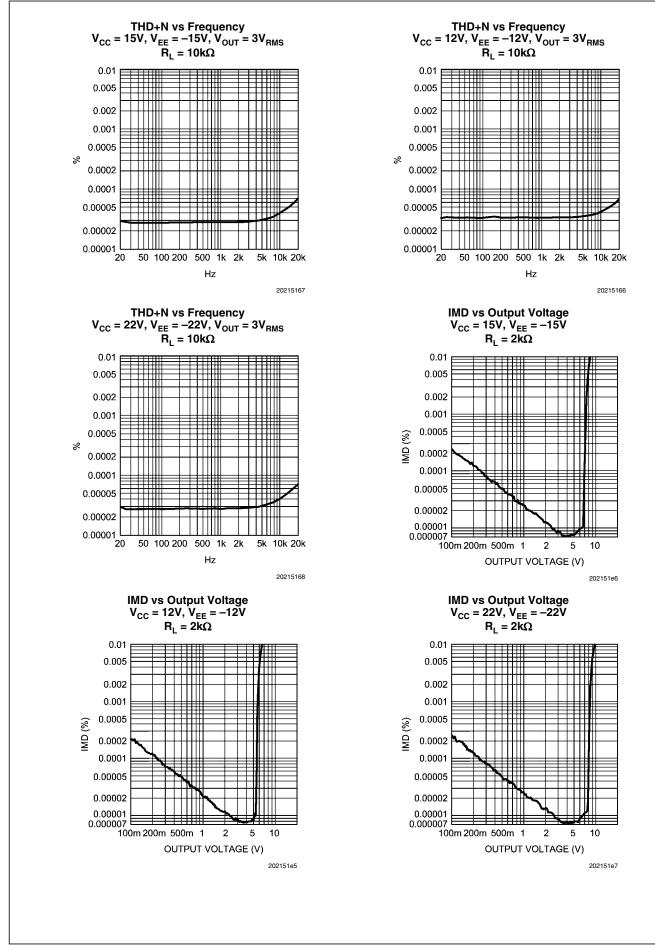
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20

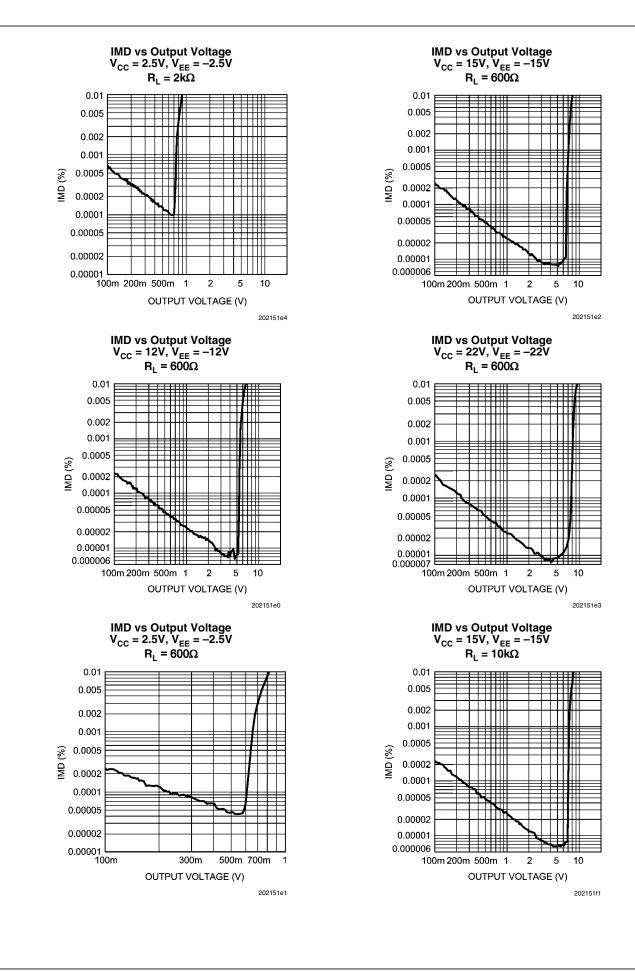
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20

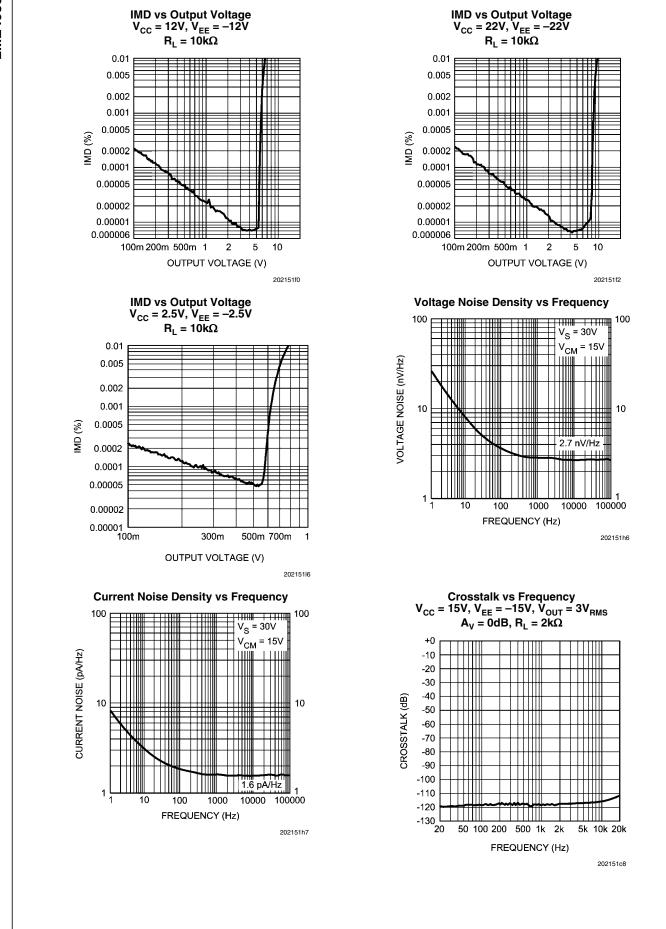




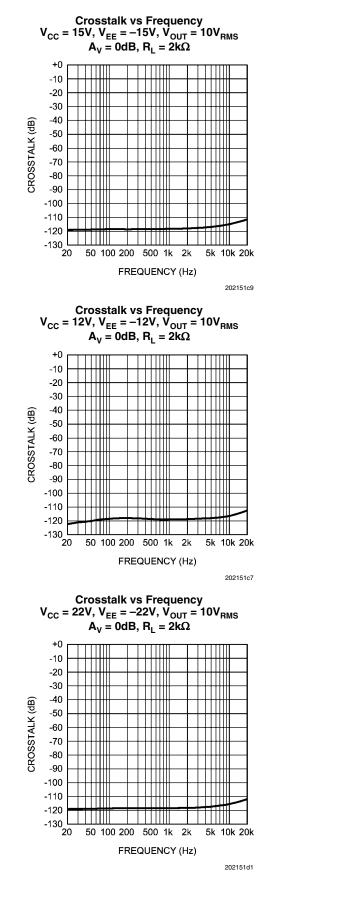


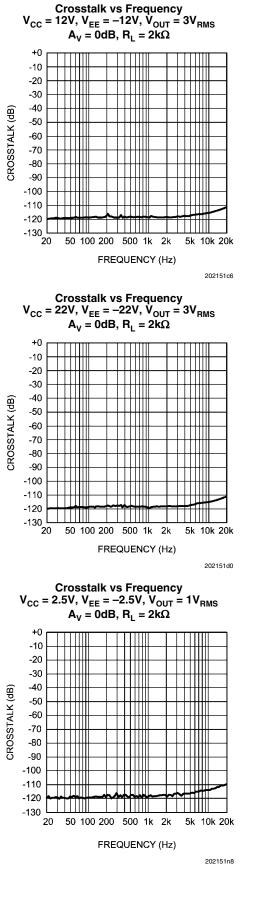


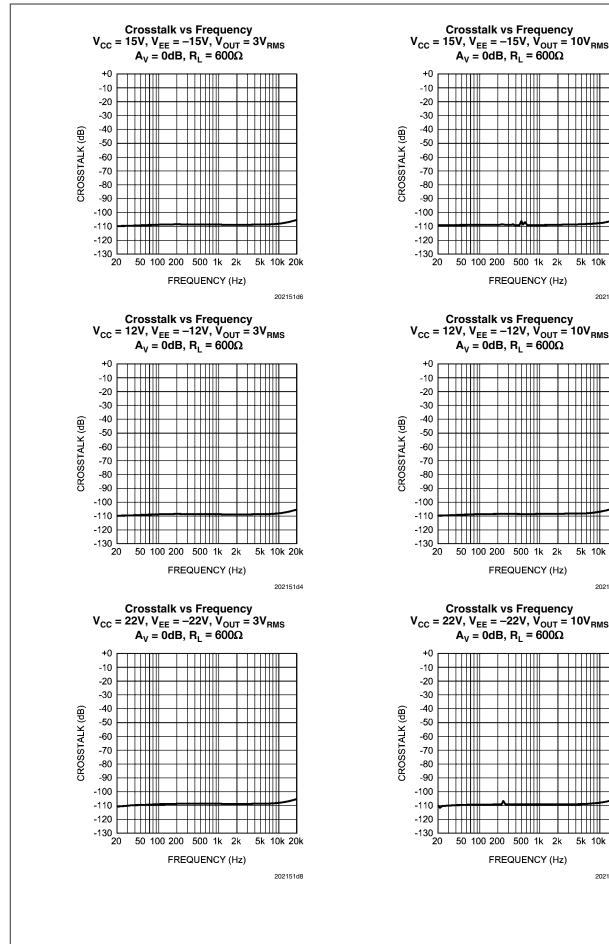












5k 10k 20k

5k 10k 20k

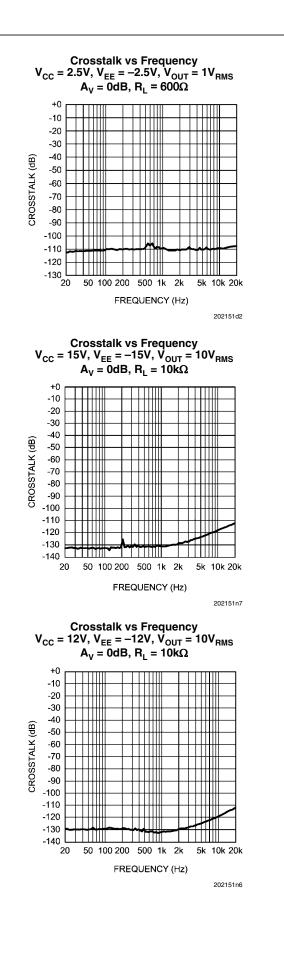
5k 10k 20k

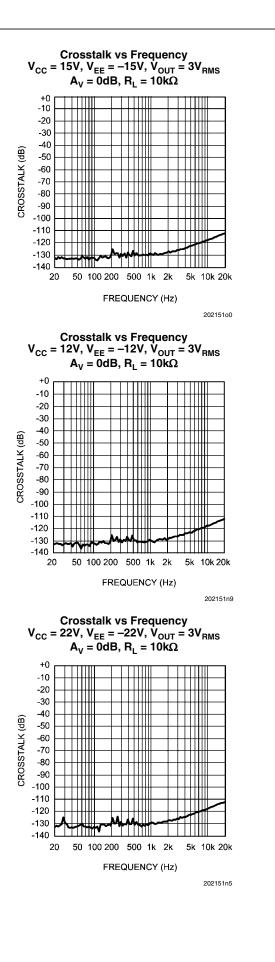
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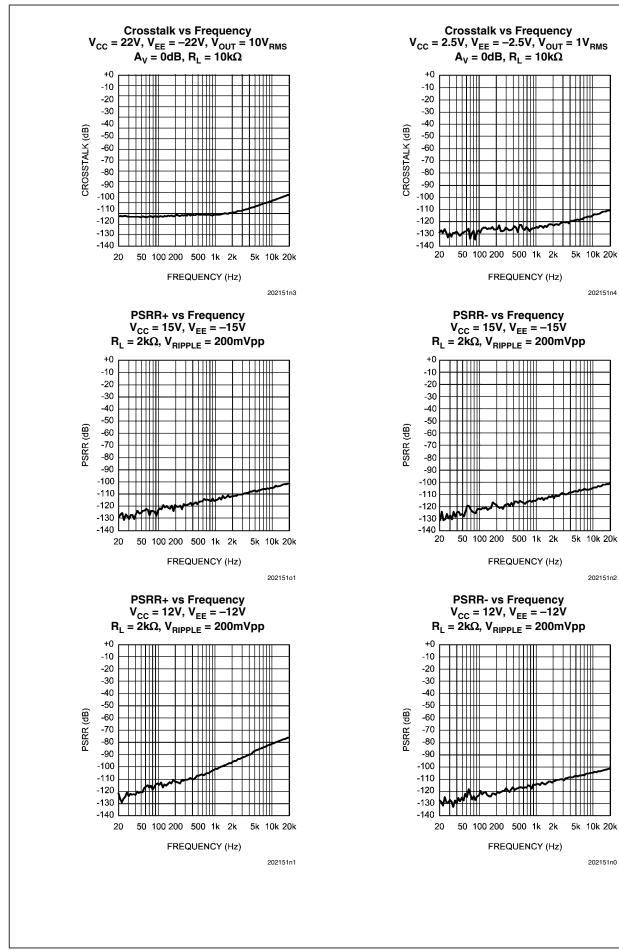
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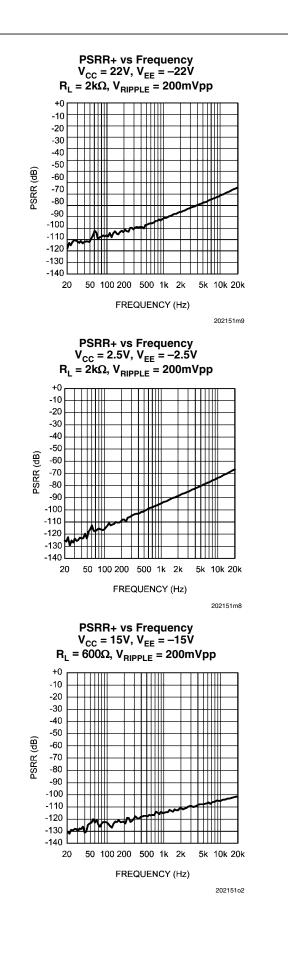


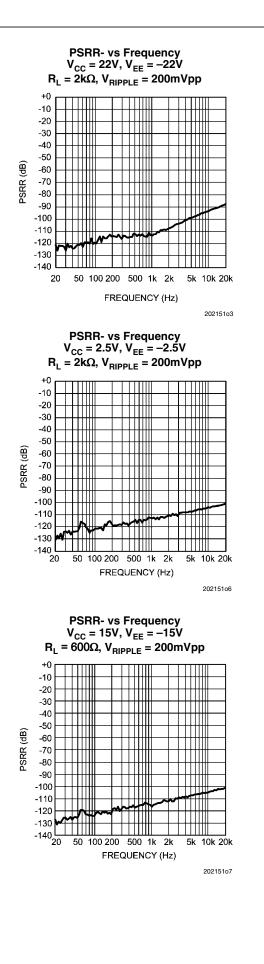




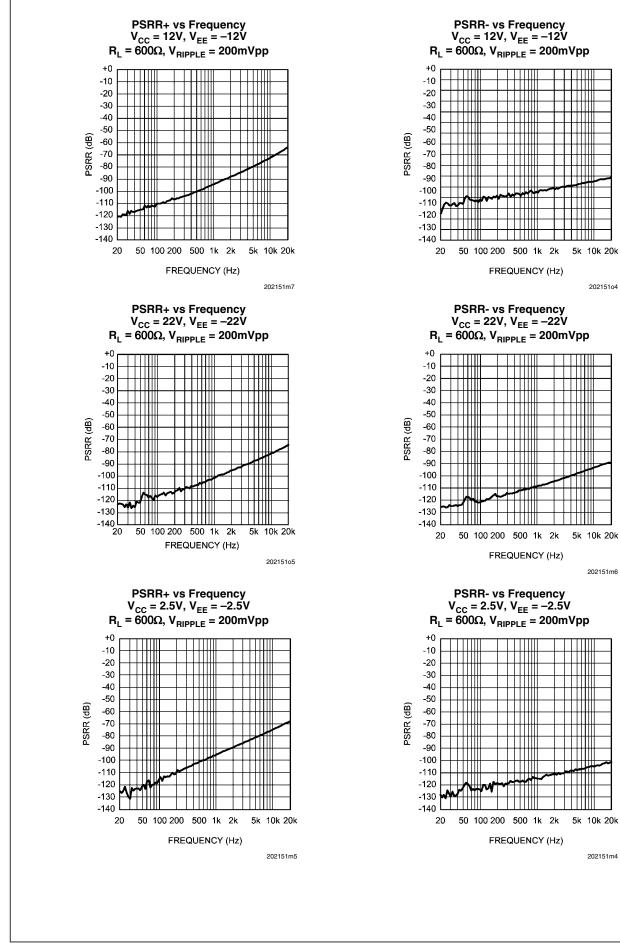
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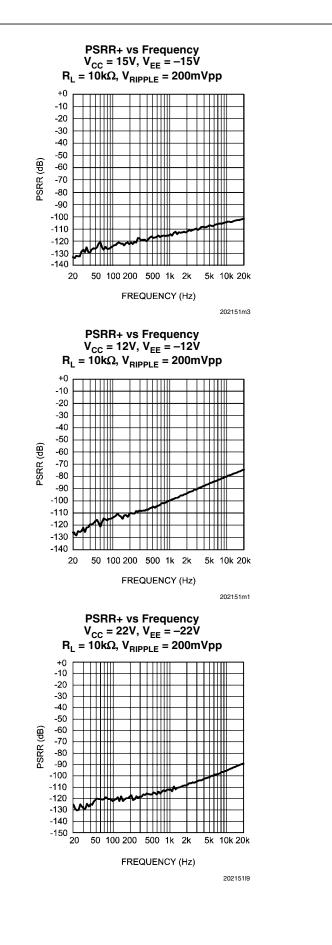


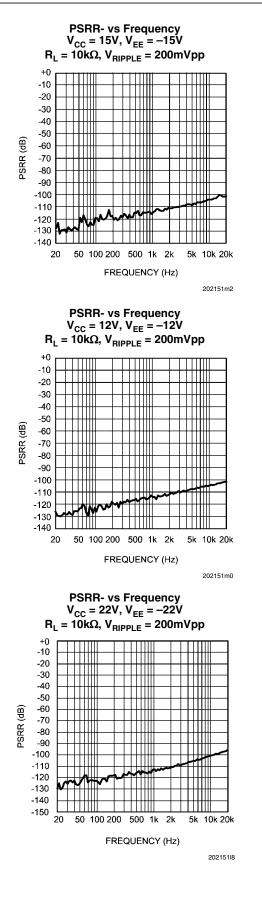
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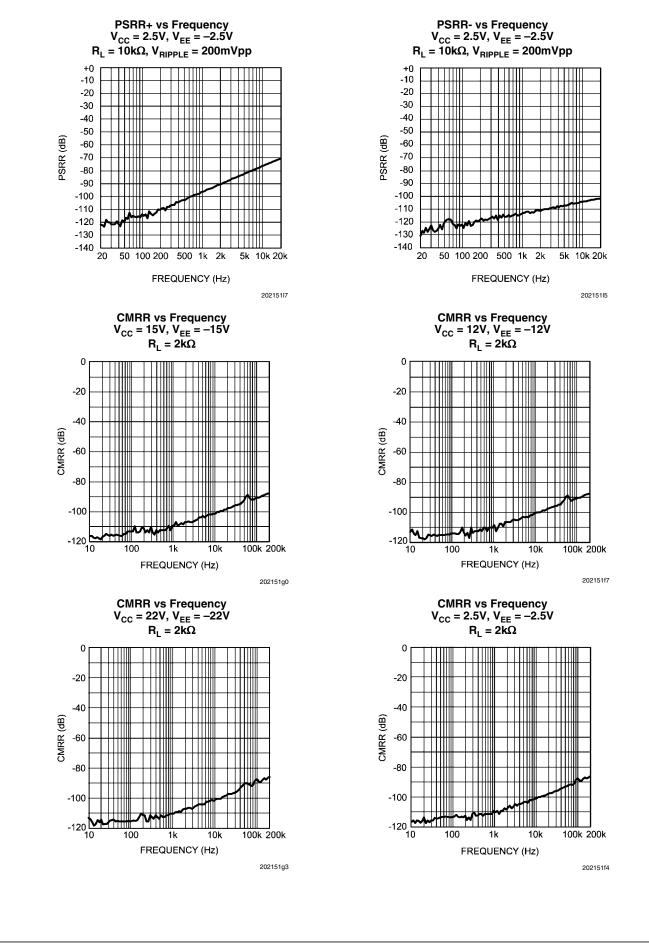
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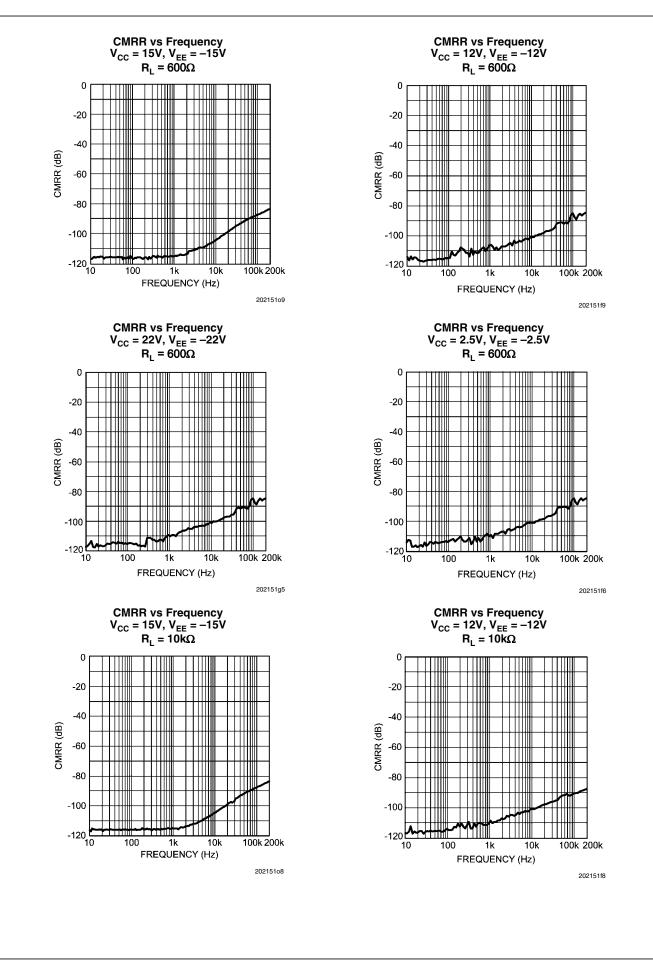




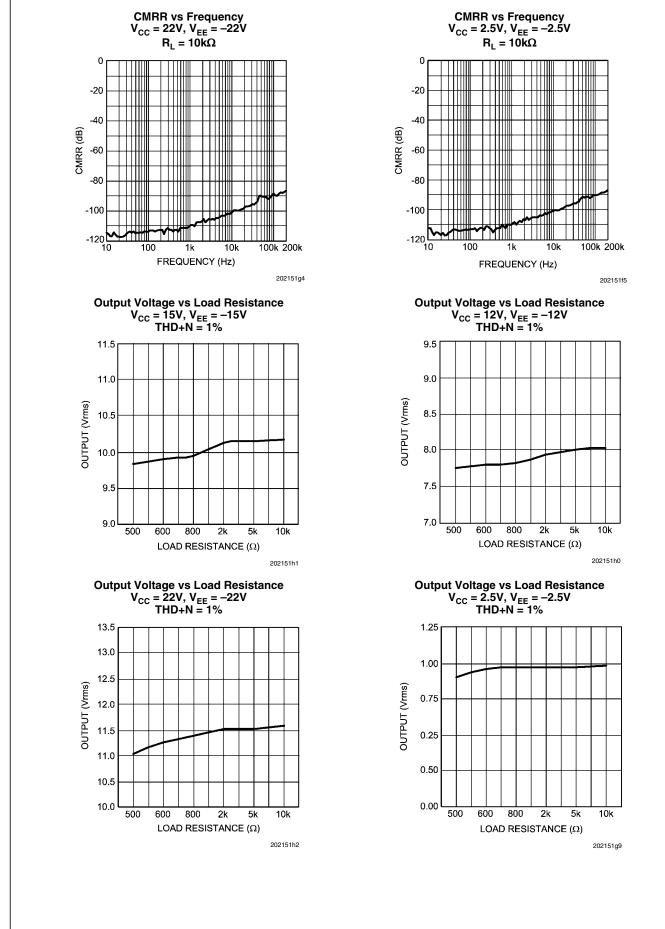
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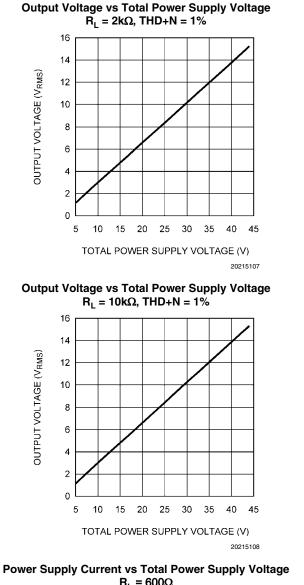
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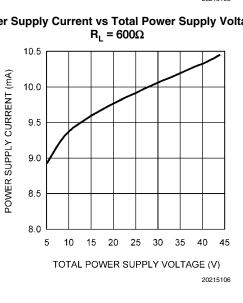


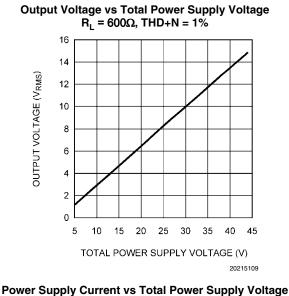
LME49860



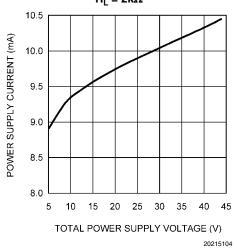
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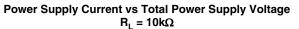


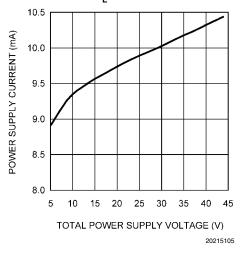




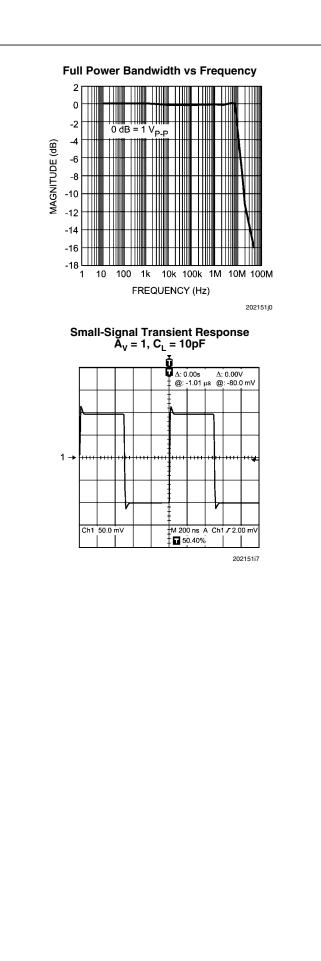
Power Supply Current vs Total Power Supply Voltage $R_L = 2k\Omega$

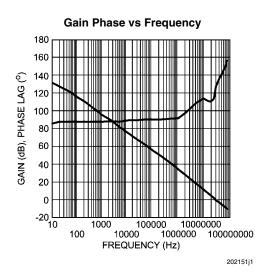


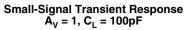


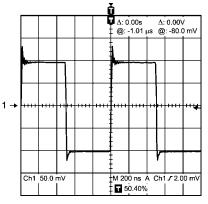


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Application Information

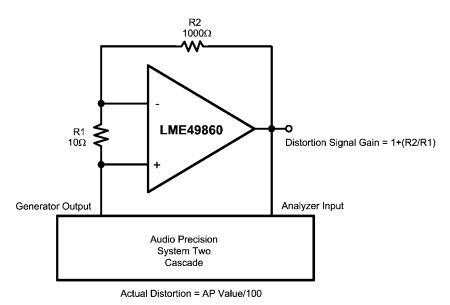
DISTORTION MEASUREMENTS

The vanishingly low residual distortion produced by LME49860 is below the capabilities of all commercially available equipment. This makes distortion measurements just slightly more difficult than simply connecting a distortion meter to the amplifier's inputs and outputs. The solution, however, is quite simple: an additional resistor. Adding this resistor extends the resolution of the distortion measurement equipment.

The LME49860's low residual distortion is an input referred internal error. As shown in Figure 1, adding the 10Ω resistor connected between the amplifier's inverting and non-inverting

inputs changes the amplifier's noise gain. The result is that the error signal (distortion) is amplified by a factor of 101. Although the amplifier's closed-loop gain is unaltered, the feedback available to correct distortion errors is reduced by 101, which means that measurement resolution increases by 101. To ensure minimum effects on distortion measurements, keep the value of R1 low as shown in Figure 1.

This technique is verified by duplicating the measurements with high closed loop gain and/or making the measurements at high frequencies. Doing so produces distortion components that are within the measurement equipment's capabilities. This datasheet's THD+N and IMD values were generated using the above described circuit connected to an Audio Precision System Two Cascade.



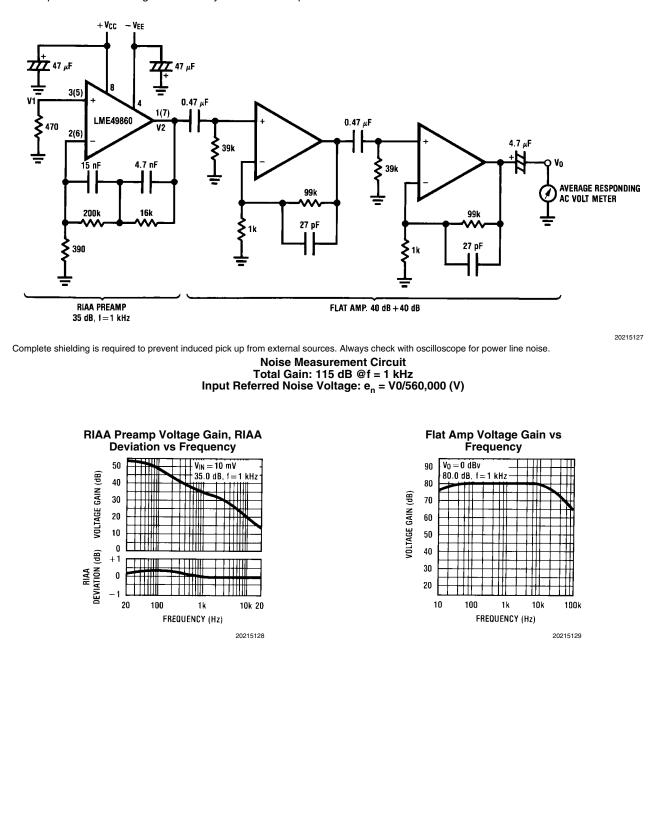
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FIGURE 1. THD+N and IMD Distortion Test Circuit

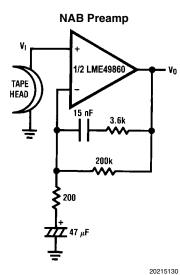
The LME49860 is a high speed op amp with excellent phase margin and stability. Capacitive loads up to 100pF will cause little change in the phase characteristics of the amplifiers and are therefore allowable.

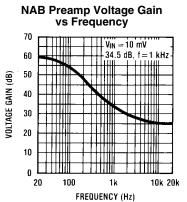
a resistor in series with the output. This resistor will also prevent excess power dissipation if the output is accidentally shorted.

Capacitive loads greater than 100pF must be isolated from the output. The most straightforward way to do this is to put



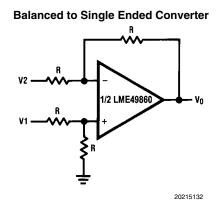
TYPICAL APPLICATIONS

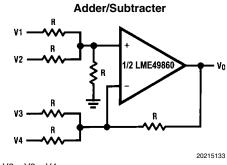


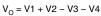


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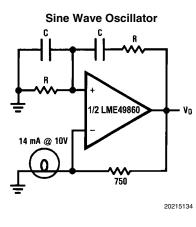
 $A_V = 34.5$ F = 1 kHz E_n = 0.38 μ V A Weighted



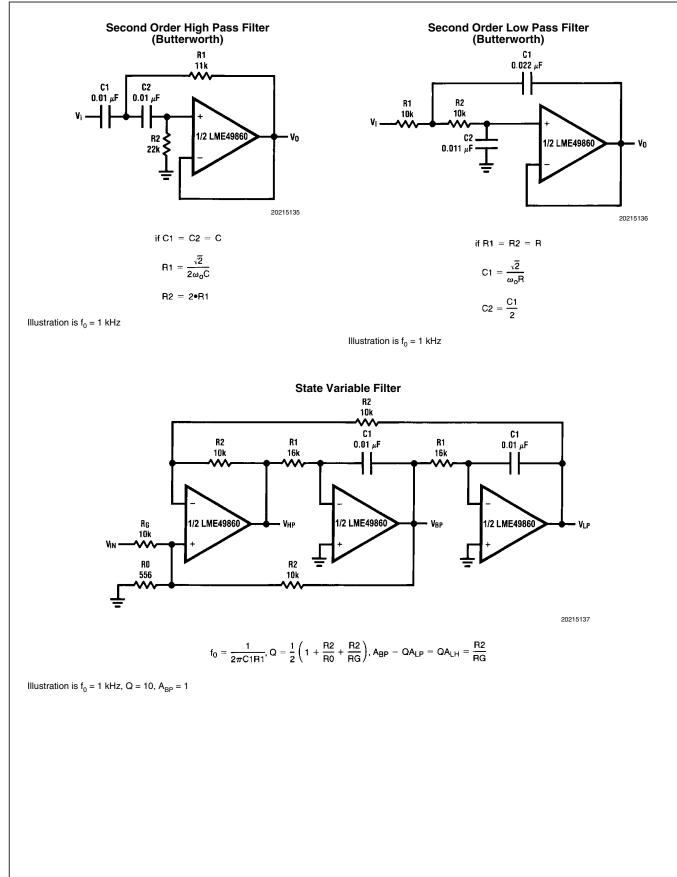




 $V_0 = V1 - V2$

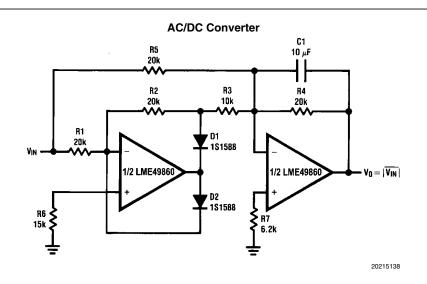




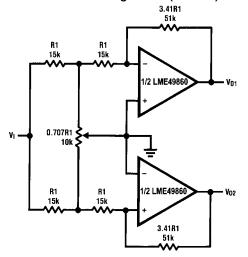


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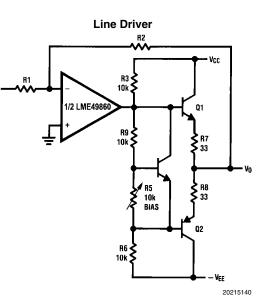
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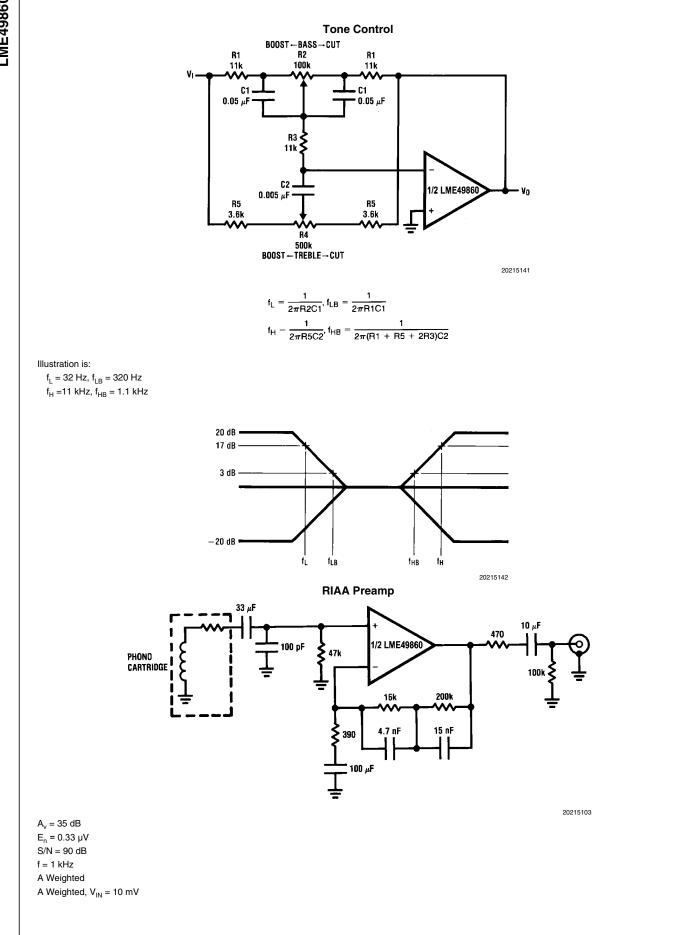


² Channel Panning Circuit (Pan Pot)

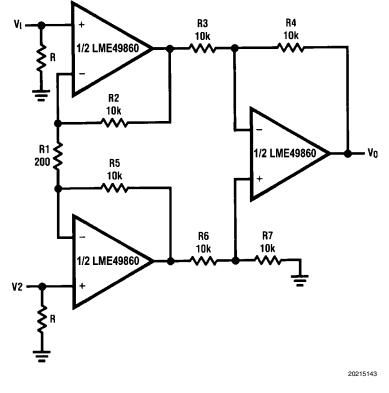


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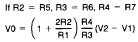
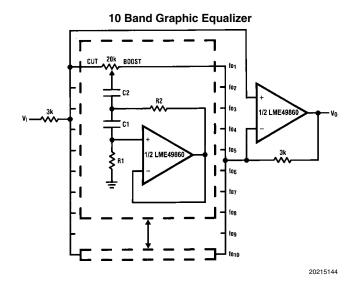


Illustration is: V0 = 101(V2 - V1)



fo (Hz)	C ₁	C ₂	R ₁	R ₂
32	0.12µF	4.7µF	75kΩ	500Ω
64	0.056µF	3.3µF	68kΩ	510Ω
125	0.033µF	1.5µF	62kΩ	510Ω
250	0.015µF	0.82µF	68kΩ	470Ω
500	8200pF	0.39µF	62kΩ	470Ω
1k	3900pF	0.22µF	68kΩ	470Ω
2k	2000pF	0.1µF	68kΩ	470Ω
4k	1100pF	0.056µF	62kΩ	470Ω
8k	510pF	0.022µF	68kΩ	510Ω
16k	330pF	0.012µF	51kΩ	510Ω

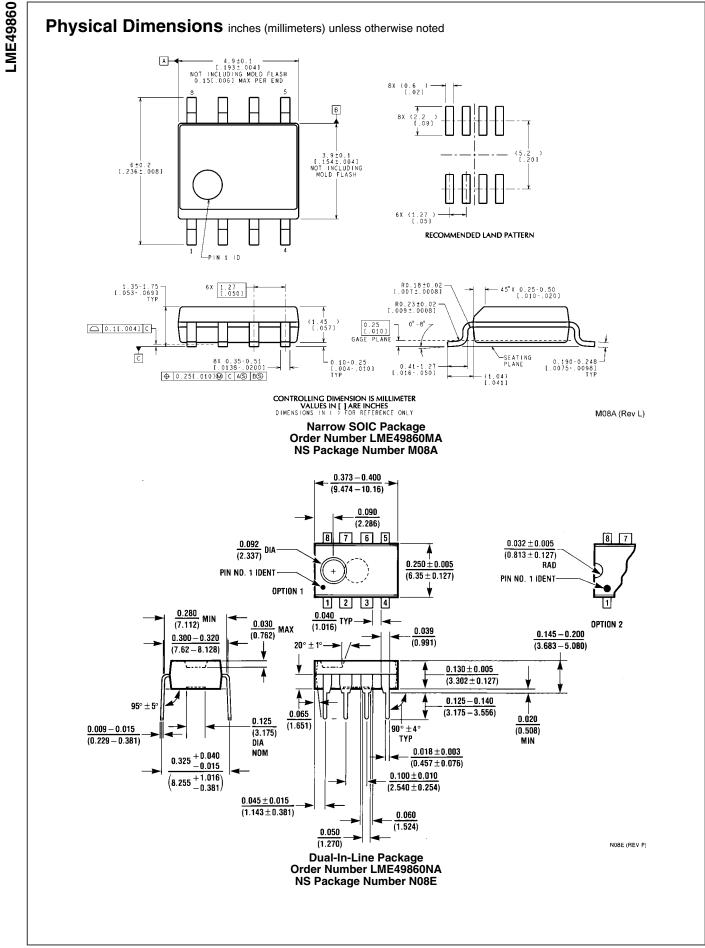
Note 9: At volume of change = $\pm 12 \text{ dB}$

Q = 1.7

Reference: "AUDIO/RADIO HANDBOOK", National Semiconductor, 1980, Page 2-61

Revision History

Rev	Date	Description
1.0	06/01/07	Initial release.
1.1	06/11/07	Added the LME49860MA and LME49860NA Top Mark Information.



Notes

Notes

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